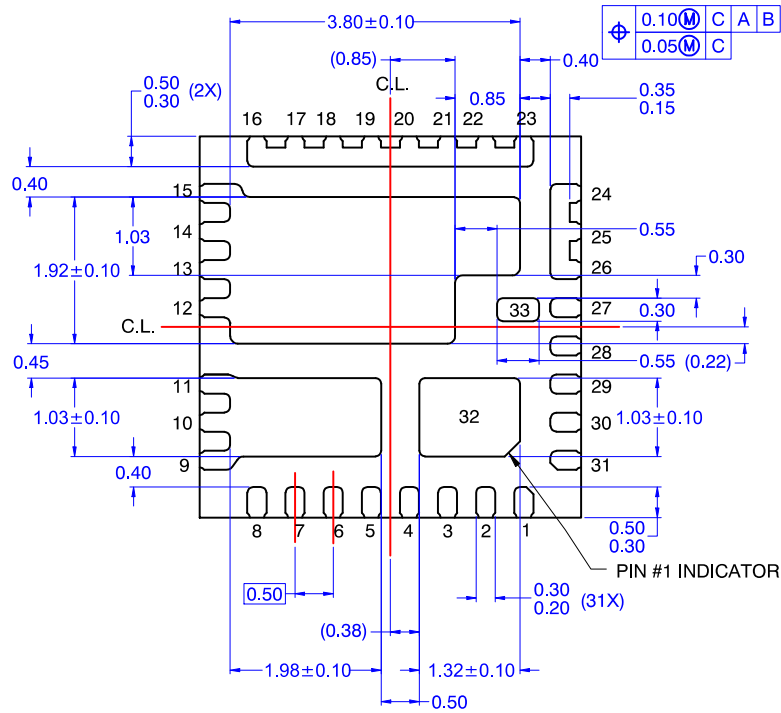


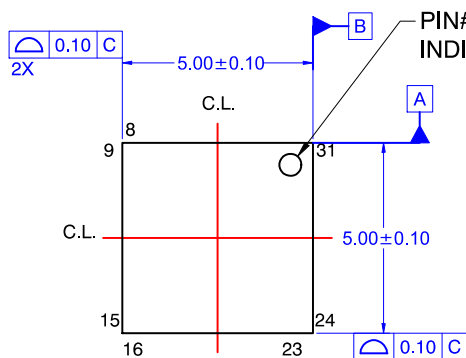


**PQFN31 5X5, 0.5P**  
**CASE 483BR**  
**ISSUE O**

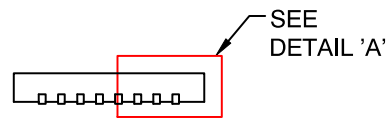
DATE 30 SEP 2016



**BOTTOM VIEW**



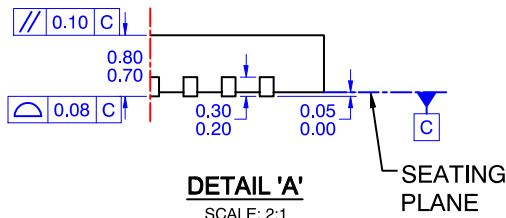
**TOP VIEW**



**FRONT VIEW**

NOTES: UNLESS OTHERWISE SPECIFIED

- A) DOES NOT FULLY CONFORM TO JEDEC REGISTRATION MO-220, DATED MAY/2005.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

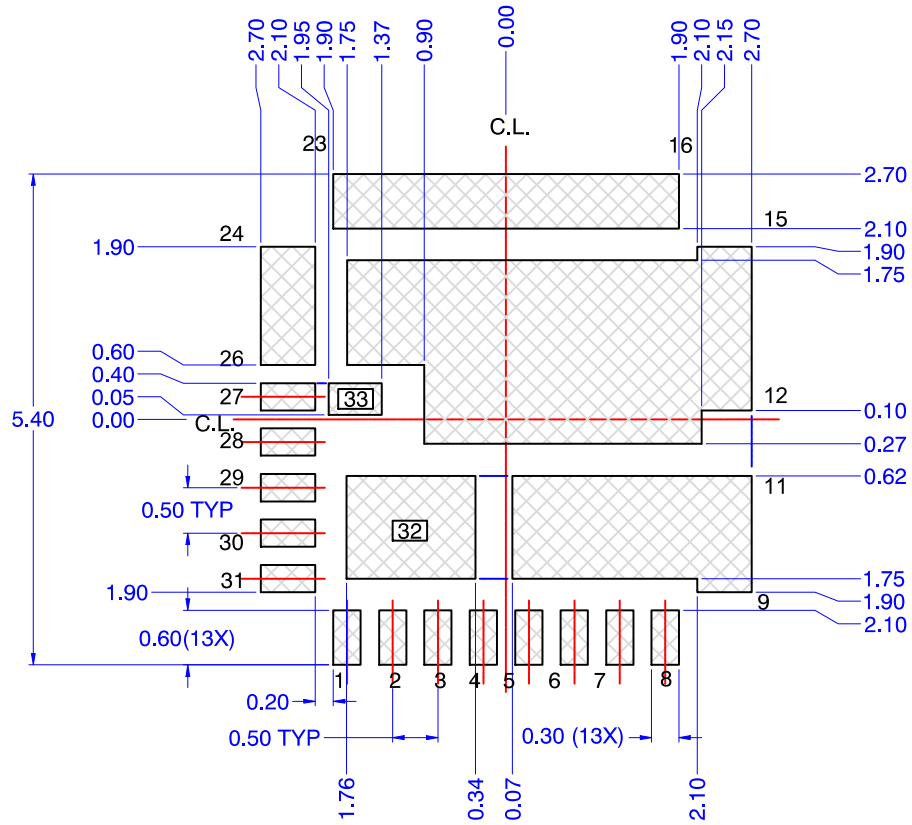


**DETAIL 'A'**  
 SCALE: 2:1

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**LAND PATTERN  
RECOMMENDATION**

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